

U.S. Patent Application Serial No. **10/709,435**
Amendment filed January 31, 2005
Reply to OA dated October 29, 2004

REMARKS:

Claims 1-5 and 7-9 are currently being considered, all of which have been amended. Claim 6 has been canceled without prejudice or disclaimer of its subject matter. No new claims have been added. Applicants believe that no new matter has been introduced.

Before turning to the cited art, a brief review of the present invention is in order. The present invention relates to a probe card. An outstanding feature of the present invention is as follows. When a contacting part of the probe of the present invention, particularly a top portion, is brought into contact with electrodes of a measurement objective, the probe is elastically deformed. Then the distal end portion thereof contacts a base plate and moves sideways on the surface of the plate so that a load applied to the probe itself can be dispersed.

Claims 1-9 stand rejected under 35 USC 102(b) as anticipated by U.S. Patent No. 6,680,536 (**Hattori '536**).

Applicants respectfully traverse this rejection.

Hattori '536 discloses a half circle arc shaped probe supported at one end thereof as shown in Fig. 2. However, the distal end of the probe is not configured to contact a substrate when contacting with electrodes of a measurement objective. Therefore, if one were to apply a

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load to the probe of **Hattori '536**, in the manner that a load is applied to the probe of the present invention, then the probe of **Hattori '536** would probably break.

Hattori '536 fails to describe, teach, or suggest the following features of claim 1, as amended: "A probe card comprising: a base plate; and a probe ... formed on and supported at one end thereof by a surface of the base plate and having a top portion located at almost the center of the probe serving as a contact surface for contacting with an electrode of a measurement objective wherein ... the top portion of the probe is brought into contact with the measurement objective and elastically deformed and thereby a distal end of said second quarter arc portion is brought into contact with said base plate", in combination with the other claimed features. Claim 1 is the base claim of claims 2-5 and 7-9.

Thus, Applicants respectfully submit that this rejection should be withdrawn.

In view of the aforementioned amendments and accompanying remarks, all claims currently being considered are in condition for allowance, which action, at an early date, is requested.

If, for any reason, it is felt that this application is not now in condition for allowance, the Examiner is requested to contact the Applicants' undersigned attorney at the telephone number

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indicated below to arrange for an interview to expedite the disposition of this case.

In the event that this paper is not timely filed, Applicants respectfully petition for an appropriate extension of time. Please charge any fees for such an extension of time and any other fees which may be due with respect to this paper, to Deposit Account No. 01-2340.

Respectfully submitted,

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